

March, 19-21 2011, Island of Kos - Greece

## Call for Papers / Invitation to Special Session SS04

### MODEL BASED TESTING AND ENGINEERING

Special Session Organizers



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In a rapidly changing Industrial technology era, higher product quality and faster time to market are key driving forces to success. Increased use of complex industrial software has increased the need for better testing methodologies. Fueled by this need, Model based engineering and testing (MDD & MBT) have evolved as suitable candidates over the last decade to face this challenge, which is evident from MBT's substantial usage in the field of aerospace, automotive, telecommunication and micro-electronics.

The purpose of this special session is to bring industry and academia under one roof serving as a forum for discussion and exchange of ideas in the context of using Model based testing and engineering in the industrial sector. This special section might also serve as a window for collaboration (e.g. future projects) between the Model-Based testing community and industries like software testing, automation, automotive, telecommunication, etc. promoting MBT's further usage.

#### Topics of interest include (but are not limited to):

- a) Model based test design and specifications
- b) Model based testing and TTCN-3
- c) Model based software development for embedded systems
- d) Model driven system/protocol engineering
- e) Modeling methodologies for testing
- f) Model based test generation techniques for Industrial systems (complex systems)
- g) Model based diagnosis
- h) Hardware-in-the-Loop testing (automation and automotive)
- i) Tool automation/simulation and tool support
- j) Experience reports on using Model Based Testing

# IEEE-ICIT'12 GREECE INTERNATIONAL CONFERENCE ON INDUSTRIAL TECHNOLOGY

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## Important dates:

Deadline for submission of full paper: ~~10th October 2011~~ 20<sup>th</sup> October 2011  
Notification of acceptance with electronic publication instruction: 22<sup>nd</sup> November 2011  
Deadline for final manuscript: 10<sup>th</sup> December 2011

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## SUBMISSION PROCEDURE

Same as for regular papers. All the instructions for paper submission are included in the conference website

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[www.isi.gr/icit12](http://www.isi.gr/icit12)